



# IMEKO

International Measurement Confederation

Technical Committee  
**TC10**

**Measurement for Diagnostics, Optimization and Control**

# MACRO meets NANO 2023

in

## Measurement for Diagnostics, Optimization and Control

### Call for papers

September 21-22, 2023  
Delft, The Netherlands

<https://www.imekotc10-2023.sztaki.hu/>

**Abstract submission:**

**April 30, 2023**

Notification of acceptance: May 30,  
2023

Final paper submission: June 30,  
2023



## Acta IMEKO

Measurement

Measurement:  
SENSORS

Selected paper will be published in:

### Scientific Topics

- Basic principles and development trends in Measurement for Diagnostics, Optimization & Control
- Sensors, signal acquisition and processing
- Failure & fault detection and prognosis
- Artificial intelligence, machine learning and data science for Diagnostics, Optimization & Control
- Industry 4.0 / 5.0 foundations, applications, trends and novelties
- Methods and algorithms for real-time Diagnostics, Optimization & Control
- Uncertainty in Diagnostics, Optimization & Control
- Digital transformation
- Internet of Things (IoT) oriented Measurement for Diagnostics, Optimization & Control
- Human aspects in Diagnostics, Optimisation & Control
- Measurement for Diagnostics, Optimization & Control for safety and risk assessment
- Product conformity assessment, quality management and process analysis
- Non-destructive Testing for Diagnostics, Optimization & Control
- Standards in Measurement for Diagnostics, Optimization & Control
- Diagnostics, Optimization & Control applications in industry, transportation, mechatronics, electronics, acoustics, urban systems, living environment, civil engineering, technology of health systems, avionics, automotive, energy, machining, green environment, water treatment and biomedical fields, etc.
- Digital twins of measurement instruments
- Optical and tactile measurement techniques
- Fabrication of the nanostructures
- Fabrication of the reference artefacts
- Nanostructure characterization techniques
- Measurement uncertainty evaluation in optical measurement techniques
- Latest developments in microscopy
- Instrument characterization methods